

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/751,372	KOERTZEN ET AL.	
Examiner	Art Unit	
James K Truiillo	2116	

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Class	Subclass	Date	Examiner
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class	Date		Examiner
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
•	DATE	EXMR		
EAST (USPAT, US-PGPUB, EPO, IPO, DERWENT, IBM_TDB), see attached; NPL: IEEE; Inventor Search/DP	7/20/2006	JKT		
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